# Notice of References Cited

Application/Control No. 10/086,025	Applicant(s)/Pater Reexamination ANDERSON ET A	
Examiner	Art Unit	
Arlen Soderquist	1743	Page 1 of 3

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,054,309	10-1991	Mettes et al.	73/1.03
	В	US-6,730,517	05-2004	Koster et al.	436/47
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
C = 15	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	61-13153	01-1986	JP	Ezawa et al.	
	0	2273561	06-1994	GB	Brand et al.	
	Р	11-6788	01-1999	JP	Morioka et al.	
	Q					
	R					
	S					
	Ť					

#### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
•	U	Stieg, S. et al, Analytical Chemistry 1980, 52, 796-800
	V	Israel, Y. et al, Analyst, 1989, 114, 1259-1265.
	w <sub>.</sub>	Lasztity, A. et al, Journal of Analytical Atomic Spectrometry 1989, 4, 761-766.
	x	Maxwell, S. L., III et al, Chemical Abtracts, 1990, 115, abstract 125715.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

## Notice of References Cited

-	Application/Control No. 10/086,025	Applicant(s)/Pater Reexamination ANDERSON ET A	
	Examiner	Art Unit	
	Arlen Soderquist	1743	Page 2 of 3

#### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
3	U	Klinkenberg, H. et al, Spectrochimica Acta, 1993, 48B, 649-661.
•	V	Goossens, J. et al, Analytica Chimica Acta 1994, 293, 171-181.
•	W	Heumann, K. G. et al, Journal of Analytical Atomic Spectrometry 1994, 9, 1351-1355.
ď	X	Hegy, G. et al, Chemical Abstracts 1996, 126, abstract 220107.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

## Notice of References Cited

Application/Control No. 10/086,025	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.	
Examiner	Art Unit	
Arlen Soderquist	1743	Page 3 of 3

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	E	US-			*
	F	US-			
	G	US-			
	Н	US-			, , , , , , , , , , , , , , , , , , ,
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

#### **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			an wes		
	0					
	Р					
	Q					
	R					
	S					
	T					

#### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
,	u	Albertus, F. et al, Analyst, 1999, 124, 1373-1381.	
.4	V	Dobney, A. et al, Analytica Chimica Acta 2000, 420, 89-94.	
	w		
	Х		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.